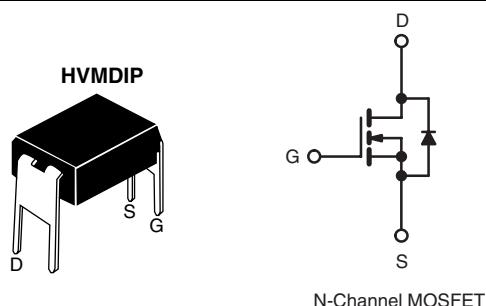


Power MOSFET

PRODUCT SUMMARY		
V _{DS} (V)	100	
R _{D(on)} (Ω)	V _{GS} = 10 V	0.27
Q _g (Max.) (nC)	16	
Q _{gs} (nC)	4.4	
Q _{gd} (nC)	7.7	
Configuration	Single	



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- For Automatic Insertion
- End Stackable
- 175 °C Operating Temperature
- Fast Switching
- Ease of Paralleling
- Compliant to RoHS Directive 2002/95/EC


RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The 4 pin DIP package is a low cost machine-insertable case style which can be stacked in multiple combinations on standard 0.1" pin centers. The dual drain serves as a thermal link to the mounting surface for power dissipation levels up to 1 W.

ORDERING INFORMATION	
Package	HVMDIP
Lead (Pb)-free	IRFD123PbF SiHFD123-E3
SnPb	IRFD123 SiHFD123

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	100	
Gate-Source Voltage		V _{GS}	± 20	V
Continuous Drain Current	V _{GS} at 10 V	I _D	1.3 0.94	A
Pulsed Drain Current ^a		I _{DM}	10	
Linear Derating Factor			0.0083	W/°C
Single Pulse Avalanche Energy ^b		E _{AS}	100	mJ
Repetitive Avalanche Current ^a		I _{AR}	1.3	A
Repetitive Avalanche Energy ^a		E _{AR}	0.13	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	1.3	W
Peak Diode Recovery dV/dt ^c		dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 25 V, starting T_J = 25 °C, L = 22 mH, R_g = 25 Ω, I_{AS} = 2.6 A (see fig. 12).

c. I_{SD} ≤ 9.2 A, dI/dt ≤ 110 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

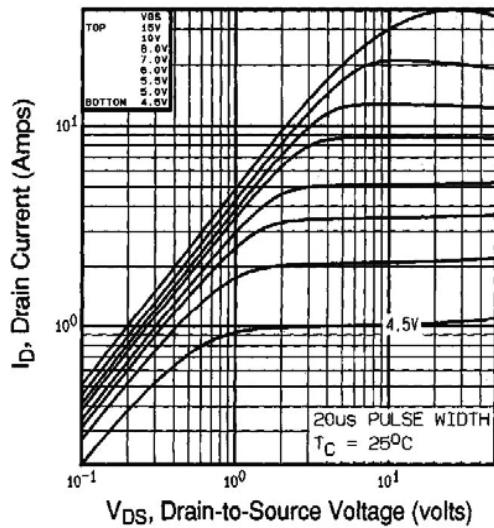
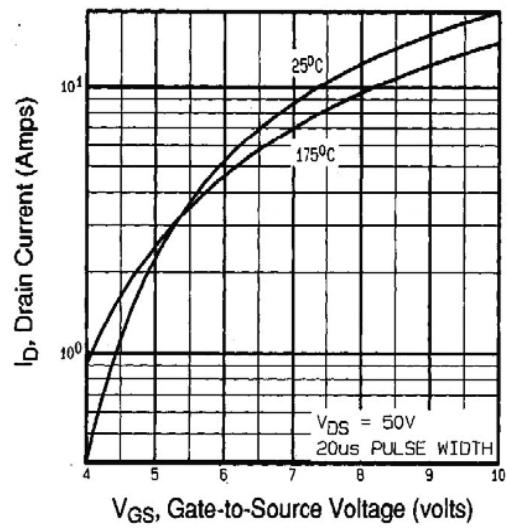
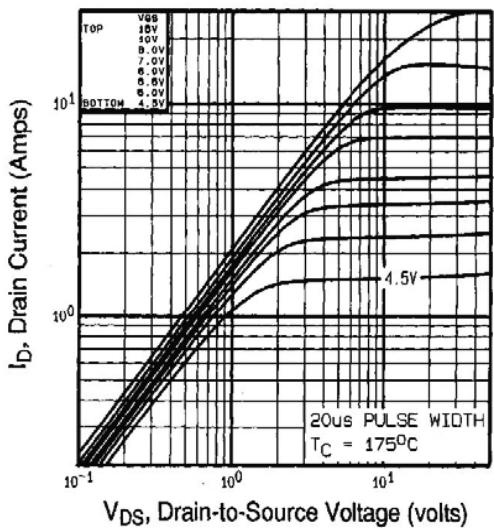
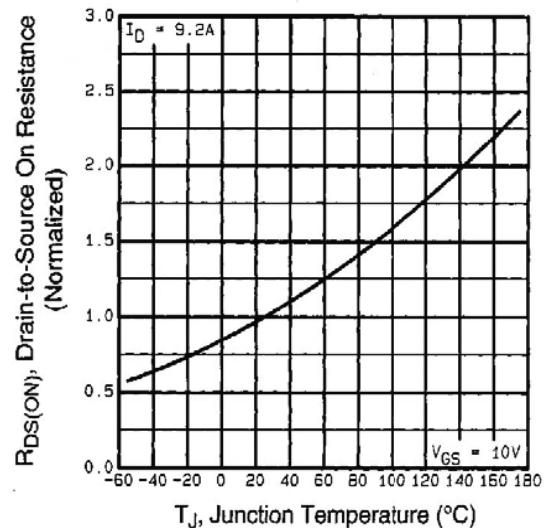
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	120	°C/W

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	100	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	0.13	-	V°C	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 80 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150^\circ\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 0.78 \text{ A}^b$	-	-	0.27	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 0.78 \text{ A}^b$		0.80	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$ $V_{DS} = 25 \text{ V}$ $f = 1.0 \text{ MHz}$, see fig. 5		-	360	-	pF	
Output Capacitance	C_{oss}			-	150	-		
Reverse Transfer Capacitance	C_{rss}			-	34	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 9.2 \text{ A}$, $V_{DS} = 80 \text{ V}$ see fig. 6 and 13 ^b	-	-	16	nC	
Gate-Source Charge	Q_{gs}			-	-	4.4		
Gate-Drain Charge	Q_{gd}			-	-	7.7		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 50 \text{ V}$, $I_D = 9.2 \text{ A}$ $R_g = 18 \Omega$, $R_D = 5.2 \Omega$, see fig. 10 ^b		-	6.8	-	ns	
Rise Time	t_r			-	27	-		
Turn-Off Delay Time	$t_{d(off)}$			-	18	-		
Fall Time	t_f			-	17	-		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	nH	
Internal Source Inductance	L_S			-	6.0	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.3	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	10		
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}$, $I_S = 1.3 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	2.5	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_F = 9.2 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	130	260	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.65	1.3	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_C = 175\text{ }^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

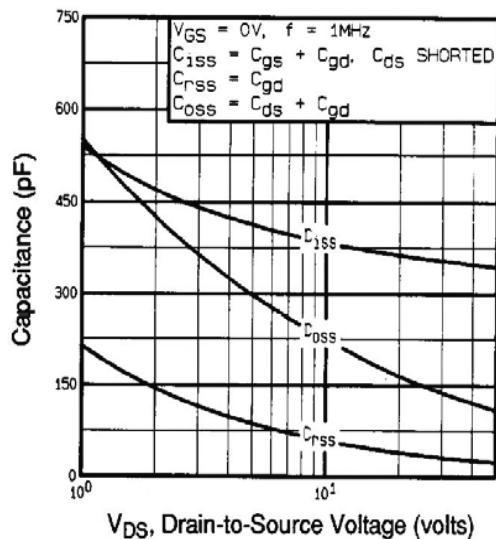


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

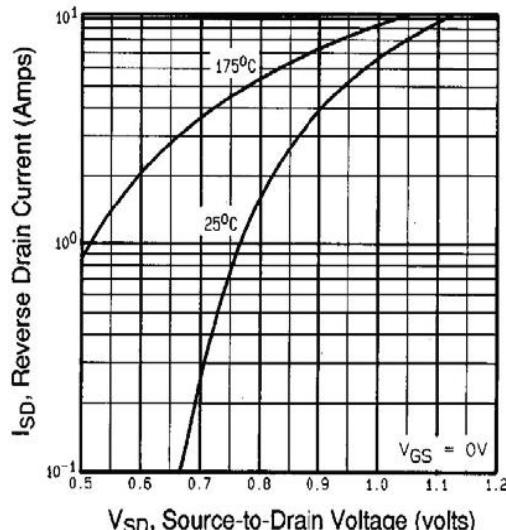


Fig. 7 - Typical Source-Drain Diode Forward Voltage

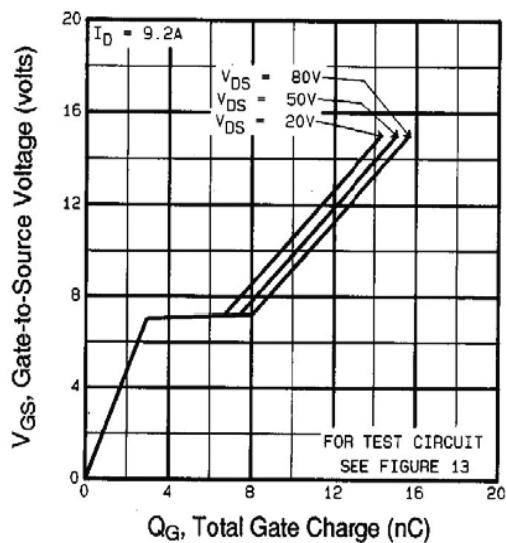


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

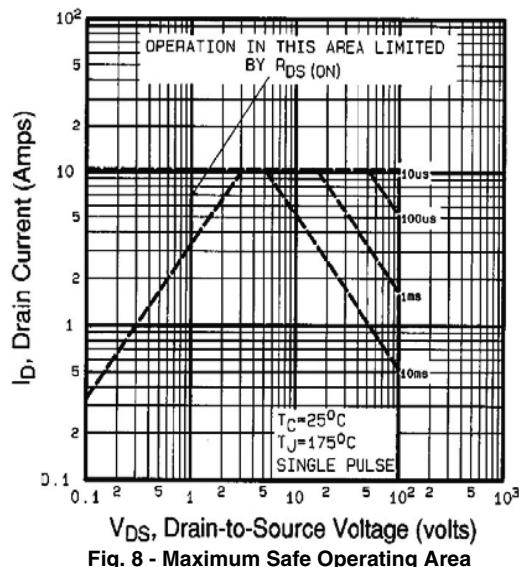


Fig. 8 - Maximum Safe Operating Area

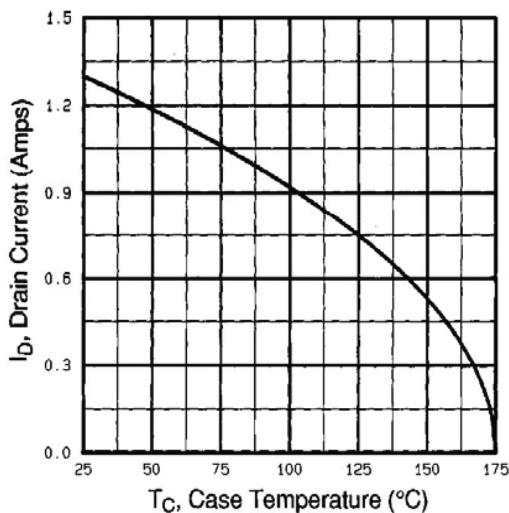


Fig. 9 - Maximum Drain Current vs. Case Temperature

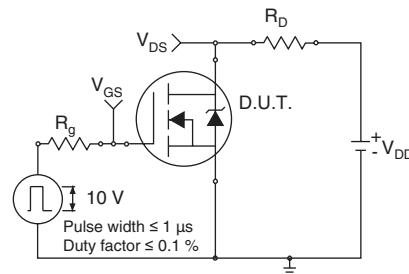


Fig. 10a - Switching Time Test Circuit

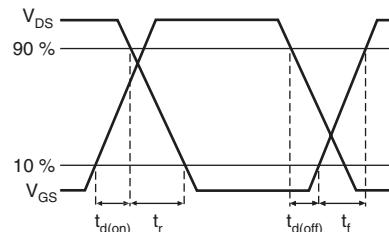


Fig. 10b - Switching Time Waveforms

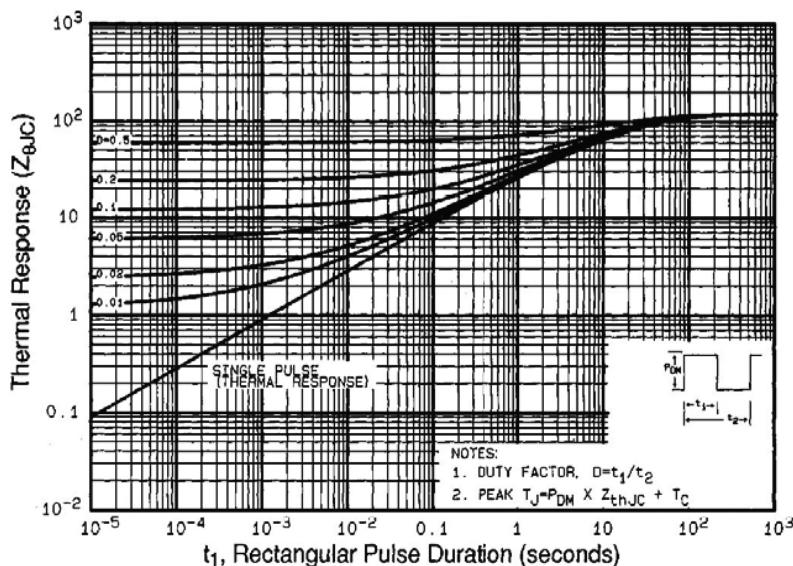


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

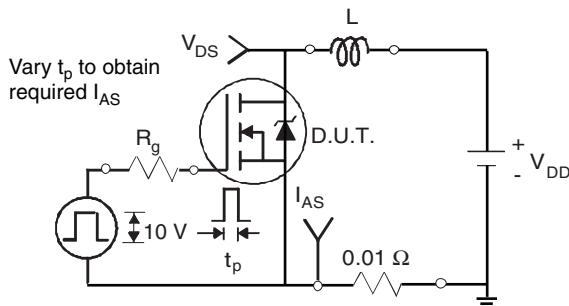


Fig. 12a - Unclamped Inductive Test Circuit

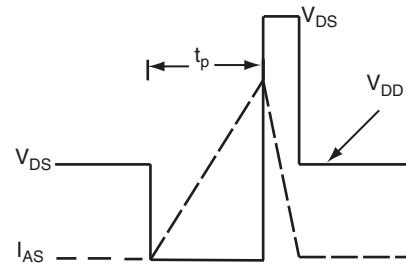


Fig. 12b - Unclamped Inductive Waveforms

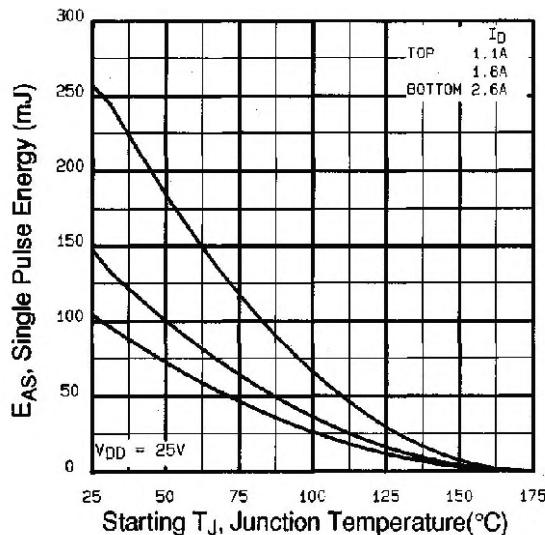


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

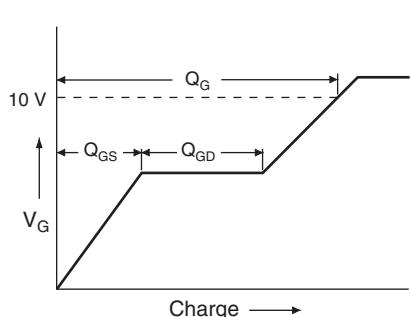


Fig. 13a - Basic Gate Charge Waveform

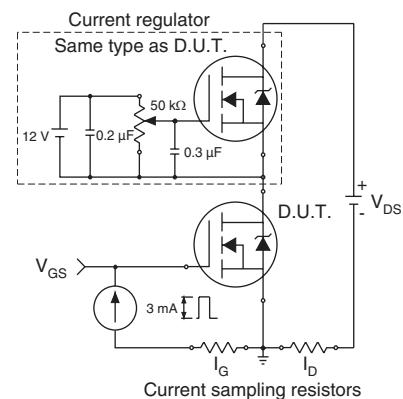
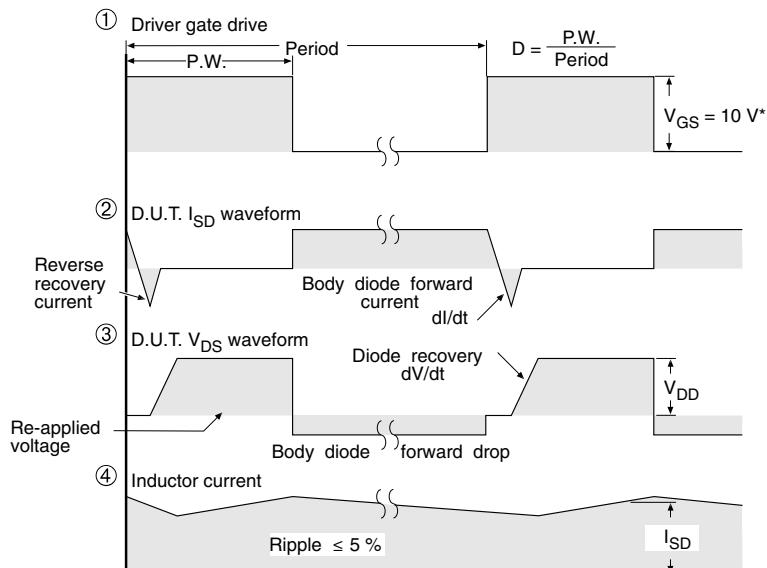
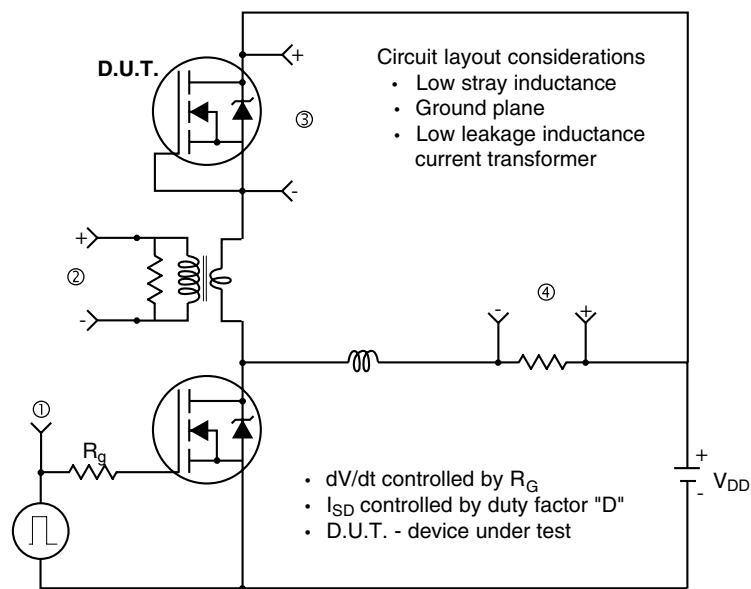


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices and 3 V drive devices

Fig. 14 - For N-Channel

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